

Correlating Qualitative Surface Profile Assessment Methods to Quantitative Methodology on Prepared Concrete Substrates

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AMPP values your input. To provide feedback on this standard, please contact: standards@ampp.org

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Foreword, Scope, Rationale.....	5
Referenced Standards.....	6
General	6
Descriptions of Methodologies Used.....	6
Methodology 1: Surface Profile Measurements from ICRI Concrete Surface Profile (CSP) 1-7 Using a Digital Depth Micrometer (ASTM D8271).....	6
Methodology 2: Surface Profile Measurements from TACM Concrete Surface Profile (CSP) 1-7 using a Digital Depth Micrometer (ASTM D8271).....	10
Methodology 3: Surface Profile Measurements from Epoxy Putty Impressions Created from Epoxy Castings of ICRI Concrete Surface Profile (CSP) 1-7 using a Specialty Two-sided Depth Micrometer (ASTM D7682, B)	11
Methodology 4: Surface Profile Measurements from Epoxy Putty Impressions Created from TACM Concrete Surface Profiles (CSP) 1-7 using a Specialty Two-side Depth Micrometer (ASTM D7682, B)	12
Results	12
Results of Methodology 1—Readings From Epoxy Castings of ICRI CSP 1-7 Using Digital Depth Micrometer (ASTM D8271).....	14
Results of Methodology 2—Readings from TACM CSP 1-7 Using Digital Depth Micrometer.....	15
Results of Methodology 3—Readings from Epoxy Putty Impressions Created from Epoxy Castings of ICRI CSP 1-7 Using Specialty Two-Sided Micrometer.....	16
Results of Methodology 4—Readings from Epoxy Putty Impressions Created from TACM CSP 1-7 Using Specialty Two-Sided Micrometer.....	17
Discussion	18
Summary	18
Figures	
Figure 1 ICRI CSP Chip Casting Apparatus & Materials.....	7
Figure 2 The Silicone Mold of ICRI CSP Chip 3.....	8
Figure 3 Beginning to Add Silicone Molding Compound to an ICRI CSP Chip.....	8
Figure 4 The Epoxy Cast ICRI CSP Chips 1-7.....	9
Figure 5 Close-Up of the Cast ICRI CSP Chip 3.....	9
Figure 6 Digital Concrete Surface Profile Depth Micrometer	10
Figure 7 TACM CSP Concrete Surface Profiles.....	11
Figure 8 Creating Epoxy Putty Replicas of ICRI CSP Chips.....	11
Figure 9 Epoxy Castings of ICRI CSP Castings and TACM CSP Chips.....	14
Figure 10 Correlating Qualitative Surface Profile Assessment Methods to Quantitative Methodology on Prepared Concrete.....	13

Figure 11	Correlating Qualitative Surface Profile Assessment Methods to Quantitative Methodology on Prepared Concrete, Using the Averaging Method for Epoxy Putty Measurements	13
Figure 12	Readings from ICRI CSP 1-7 Epoxy Castings Using ASTM D8271 Digital Depth Micrometer.....	14
Figure 13	Readings from TACM CSP 1-7 Using ASTM D8271 Digital Depth Micrometer	15
Figure 14	Methodology 3—Epoxy Putty (ASTM D7682 Method B) on Cast Replicas	16
Figure 15	Part 4 -- Epoxy Putty (ASTM D7682 Method B) on TACM Panels.....	17
 Tables		
Table 1	ICRI CSP Chip Designation and Represented Surface Preparation.....	7
Table 2	TACM CSP Chip Designation and Represented Surface Preparation.....	10
Table 3	Methodology 1—ASTM D8271 on Cast Replicas of ICRI CSP Chips	14
Table 4	Methodology 2—ASTM D8271 on TACM Chips	15
Table 5	Methodology 3—Epoxy Putty (ASTM D7682 Method B) on Cast Replicas	16
Table 6	Part 4—Epoxy Putty (ASTM D7682 Method B) on TACM Panels	17
Table 7	Lookup Table (Conversion of ICRI and TACM Panels to Mills and Microns)	18

Foreword

Coating/lining manufacturers and/or facility owners frequently specify cleaning and roughening of the concrete surface prior to product installation. The specifications may reference qualitative methods including visual assessments using comparison coupons or quantitative methods including surface profile depth measurements. However, prior to this Technical Report, there was no known data to inform a conversion between qualitative and quantitative methods. The outcomes of this Technical Report enable coating manufacturers, engineers, specifiers, and contractors to convert well-established qualitative methods to quantitative values based on an interlaboratory experiment. While current quantitative methods can measure up to 6 mm (250 mils), extremely rough concrete surfaces (exceeding ~1.5 mm, or ~50 mils) were not included in the experiment due to the inability to stabilize the instrument probe and obtain accurate data.

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Scope

This Technical Report describes an experimental process that was used to create a “look up Table” for correlating qualitative descriptions of concrete roughness to quantitative values of surface profile.

Rationale

Proper bonding of coatings and linings to concrete surfaces requires proper cleaning of the concrete and also frequently requires the concrete surface to be roughened to increase its surface area. Abrasive blast cleaning, acid etching, or various impact/scarifying power tools can be used to augment the natural roughness of the concrete surface. The resulting surface profile depth can influence coating/lining adhesion and performance.

The surface profile (roughness) of prepared concrete can be assessed visually using Concrete Surface Profile (CSP) Chips such as those described in Guideline No. 310.2R, produced by the International Concrete Repair Institute (ICRI), or by creating a replica of the prepared surface using an epoxy putty as described in ASTM D7682 and comparing it to the specified ICRI chip (Method A) or taking depth micrometer measurements from the replica (Method B). ASTM D8271 describes a procedure for acquiring measurements directly from the prepared concrete using an electronic depth micrometer. The Technical Applications for Concrete Materials (TACM)⁽¹⁾ group also produces concrete samples that are mechanically (or chemically) processed by the actual methods used to obtain the ICRI CSP® profiles. AMPP SP21513 addresses the frequency and acceptability of concrete surface profile measurements using any of these methods.

The CSP Chips produced by ICRI are arguably the most widely recognized and most frequently specified method to assess concrete roughness; however, this method (as well as the TACM concrete samples) is qualitative and requires some judgment. The procedures described in ASTM D7682 (Method B) and ASTM D8271 are quantitative but are not widely specified. There is value in correlating the qualitative and quantitative methods of assessing the surface profile of prepared concrete so that specifiers can specify either, without inadvertently invoking contradictory requirements.

⁽¹⁾ Technical Applications for Concrete Materials (TACM) is a privately held subsidiary of Artflor, Inc., www.technicalconcrete.com.